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## FTM-Lite++

### Programming Library for Film Thickness Measurement on TranSpec<sup>®</sup> and FTM-Lite Gauges

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For developing your own film thickness measurement applications using our TranSpec and FTM-Lite film thickness gauges, we provide our powerful and very easy-to-use programming library **FTM-Lite++**.

With FTM-Lite++ the entire spectra data acquisition, like scanning the diode array, raw data averaging, dark current correction and the spectra normalization is fully encapsulated in just a few simple function calls. The measured interference spectra will be evaluated in real-time for either single or double layer film thickness using the same high precise Fast-Fourier Transform (FFT) algorithm as our FTM-ProVis Professional and FTM-ProVis Lite software packages.

FTM-Lite++ gives you full access to all measured spectra (including the raw data), the computed FFT spectrum and film thickness results and lets you create the so-called Spectra-Recorder files, which can be viewed and re-processed using FTM-ProVis. This way you can easily view and check all measurements executed with your application and FTM-Lite++.

- Runtime licensed Dynamic Link Library (DLL) providing standard C calls  
Compatible with common C/C++ compilers, Visual Basic and VBA (Excel), LabView
- Extensive parameter checks and measurement status verification  
You hardly can do anything wrong when working with FTM-Lite++
- Supports external I/O module with 8-channel TTL and 4-channel analog out
- Detailed user's manual as compiled HTML file and printed PDF document
- Demo software as Windows console application, including C/C++ source code
- See next page for a programming example!

Technical specifications on next page ►



## FTM-Lite++ Programming Library • Technical Specifications

August 2008, related to version 2.0, without guarantee, subject to changes.

### Minimum Hardware and Software Requirements

- PC/Laptop with at least Pentium-4, Windows XP or Vista
- C/C++ development system (MS Visual Studio recommended), Delphi, Visual Basic or VBA, LabView
- TranSpec or FTM-Lite Film Thickness Gauge
- FTM-ProVis Lite software is recommended, but not required

### Programming Example

```
// Step 1: open and initialize spectrometer
FTMLITE_SPECHARDWARE sSpecHardwareInfo;
FTMLite_OpenSpectrometer( FTMLITE_TRANSPEC_LITE, &sSpecHardwareInfo );

// Step 2: setup measurement parameter:
FTMLITE_MEASPARA sMeasPara;
sMeasPara.dIntegrationTime = 20.0;           // 20 ms integration time
sMeasPara.bEnableAverage = 1;             // averaging on
sMeasPara.iNumberAverage = 10;          // 10 scans for averaging
FTMLite_SetMeasPara( &sMeasPara );       // notify settings to spectrometer

// Step 3: perform measurement of an averaged Dark Current
FTMLite_CloseShutter();                   // close shutter of connected lamp
FTMLite_RunMeasDarkCurrent();            // start measurement
FTMLITE_SPECSTATUS sSpecStatus;
FTMLite_GetSpecStatus( &sSpecStatus );    // wait until measurement is done
while ( sSpecStatus.bRunDarkCurrent )
    FTMLite_GetSpecStatus( &sSpecStatus );

// Step 4: perform measurement of an averaged and Dark Current corrected Reference spectrum
FTMLite_OpenShutter();                   // open shutter of connected lamp
FTMLite_RunMeasReference();              // start measurement
FTMLite_GetSpecStatus( &sSpecStatus );    // wait until measurement is done
while ( sSpecStatus.bRunReference )
    FTMLite_GetSpecStatus( &sSpecStatus );

// Step 5: setup film thickness evaluation parameter (simple example)
FTMLITE_EVALPARA sEvalPara;
sEvalPara.bSpecEvalRangeFull = 1;        // use entire interference spectrum for evaluation
sEvalPara.bPeakSearchRangeFull = 1;     // search entire FFT spectrum for peak
sEvalPara.dReflIndex = 1.56;           // refraction index of the layer
FTMLite_SetSingleLayerEvalPara( &sEvalPara ); // initialize single layer evaluation

// Step 6: measure and evaluate an averaged and Dark Current corrected interference spectrum
FTMLite_RunMeasInterference();           // start measurement
FTMLite_GetSpecStatus( &sSpecStatus );    // wait until measurement is done
while ( sSpecStatus.bRunInterference )
    FTMLite_GetSpecStatus( &sSpecStatus );
FTMLITE_RESULT sResult;
FTMLite.EvalSingleLayer( &sResult );     // evaluate interference spectrum

// Done! Aside from other information, the structure <sResult> now contains:
sResult.dThickness           // the film thickness in microns
sResult.bIsPlausible         // thickness seems to be plausible or not
sResult.sDateAndTime        // the date and time (microsecond resolution) of the measurement
```

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